

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination OPHARDT, HEINER	
		Examiner Dah-Wei D. Yuan	Art Unit 1745	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,601,936 A	02-1997	Dudfield et al.	429/13
	B	US-6,648,085	11-2003	Nagura et al.	180/65.1
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2001-247200	09-2001	Japan	Okaniwa	H01M 8/04
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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